

Search Notes

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10/784,820

Examiner

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Applicant(s)/Patent under
Reexamination

YIP ET AL.

Art Unit

2193

SEARCHED

Class	Subclass	Date	Examiner
708	319	3/2/2007	MAI

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor(s) search Double Patent Check Data Bases Search (see search history printout(s))	3/2/2007	MAI